

## TES detector and array production for the HOLMES experiment





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## Conclusions

- We need 300 decays/s per sample in order to reach <1 eV neutrino mass statistical sensitivity (see also A.P. Puiu's poster n. 032515);
- We optimized the microfabrication process and the TES array design in order to maximize the number of detectors.
- A dummy 3" wafer with a total of 43 stripes (1978 detectors) has been fabricated by NIST, and should be tested and implanted in Genoa (see G. Pizzigoni's poster n. 032315);
- New C<sub>p</sub> measurements on Si:Au implanted samples should be achieved in order to be sure that no excess specific heat arises at T<100 mK.